

## Updates on R&D of Nondestructive Inspection Systems for SRF Cavities Y.Iwashita, H.Tongu, Kyoto U., Uji, Kyoto, JAPAN H. Hayano, K.Watanabe, Y.Yamamoto, KEK, Ibaraki, JAPAN

## INTRODUCTION

We are developing high resolution eddy current scan and High density T-map and X-map. The high resolution eddy current scan showed 100  $\mu$ m diameter hole with 50  $\mu$ m depth that was drilled on a Nb plate. The surface mount print circuit technology is applied to the high density T-map and X-map devices, which will be ready soon to test at a vertical test bench. In addition, radiography using Xrays and neutrons are also under study. The results and status will be presented.















